Amendments to the Specification

The specification is being amended to correct typographical and clerical errors. No new subject matter is being added.

Please replace the abstract of the disclosure with the following rewritten abstract:

b1

The present invention relates to microwave resonant system Methods techniques have been developed for making dielectric measurements of materials in the near field of microwave antennas. These techniques overcome the limitations of previous devices as the size, shape, orientation, and location of a sample can have a substantial impact on dielectric measurements. A preferred embodiment uses a single feed microstrip sensor device that generates a plurality of polarizations to measure dielectric properties of an object.